

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10058173	STEFANIK ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Zhen, Li B	2194

## SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
717	171,172,173,177	6/27/2007	LZ
update	search	12/4/07	LZ
update	search	6/10/2008	LZ
update	search	11/26/2008	LZ
update	search	5/15/2009	LZ
update	search	6/18/2010	LZ

## SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST (US-PGPUB;USPAT;USOCR;EPO;DERWENT;IBMTDB) See search history printout	6/27/2007	LZ
Inventor Name Search	6/27/2007	LZ
EAST (US-PGPUB;USPAT;USOCR;EPO;DERWENT;IBMTDB) See search history printout	12/4/07	LZ
EAST (US-PGPUB;USPAT;USOCR;EPO;DERWENT;IBMTDB) See search history printout	6/10/2008	LZ
EAST (US-PGPUB;USPAT;USOCR;EPO;DERWENT;IBMTDB) See search history printout	11/26/2008	LZ
EAST (US-PGPUB;USPAT;USOCR;EPO;DERWENT;IBMTDB) See search history printout	5/15/2009	LZ
EAST (US-PGPUB;USPAT;USOCR;EPO;DERWENT;IBMTDB) See search history printout	6/18/2010	LZ

## INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>